Search Notes



Applic		

10/797,381

Examiner

James D. Stein

Applicant(s)/Patent under Reexamination

KROPP, JORG-REINHARDT

Art Unit

2874

SEARCHED				
Class	Subclass	Date	Examiner	
385	15,27,31,3 9,33,49	7/1/2005	JDS	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
See attached EAST search history	7/1/2005	JDS
IEEE and INSPEC: bidirectional coupler, lens, detector, waveguide	7/1/2005	JDS